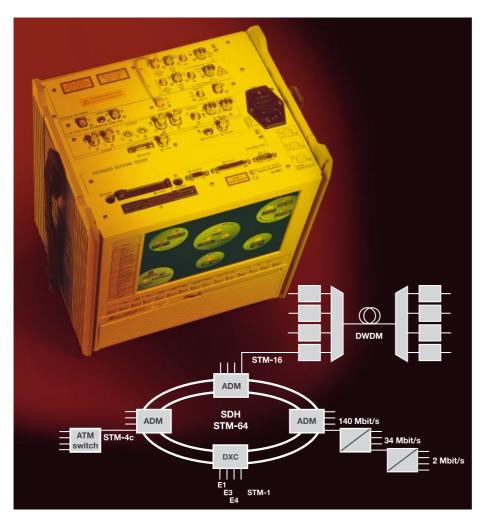


Acterna ANT-10Gig

Advanced Network Tester – SDH version



Realizing future trends

Recent years have been characterized by a dramatic increase of communications services using networks that are becoming more and more global. The Internet is a particularly high growth area. Two different technologies have developed side by side to handle the increased demand for bandwidth.

One is time-division multiplexing (TDM) of synchronous channels to give higher bit rates, the other is optical multiplexing of a large number of synchronous systems to be carried by a single fiber (DWDM). The basic idea behind both methods is to make the best possible use of available fiber capacity.

10 Gbit/s in a portable test solution

The ANT-10Gig is a subset of the ANT-20SE. It provides a unique compact and convenient solution for STM-64/OC-192 including jitter and wander testing.

It can resolve signal structures right up to the STM-64/OC-192 level and analyze them down to 64 kbit/s. Access to all standardized mapping structures is possible, including mixed structures, e.g. DS1 in STM-1 or E1 in STS-1.

The ANT-10Gig allows also testing of all concatenated signal structures currently used up to STM-64c/OC-192c.

STM-64/OC-192

For analyzing digital communications systems

Optional: Complete BERT solution n×64 kbit/s up to 10 Gbit/s

- STM-64 and OC-192 optical and electrical interface in a portable instrument
- Jitter/Wander testing at 10 Gbit/s
- Tributaries: STM-1 with all standard mappings and STM-4c, STM-16c, STM-64c, STS-3c, STS-12c, STS-48c, STS-192c
- Access to all SOH/TOH bytes
- Errors, alarms, pointers
- Internal and external simulation and analysis of overhead bytes
- BERT and V.11 interface for DCC
- High output power 0 dBm
- Receiver with optical power level display

Edition: July 2001



Configuration Guide

ANT-10Gig

		_	
Mainframe	ANT-10Gig – SDH – Mainframe	BN 3060/35	
page 3-10	includes STM-64, STM-4c, STM-16c and STM-64c BERT,		
	STM-1 mappings, Extended overhead analysis		
SONET	Electrical Interfaces at 10 Gbit/s*	BN 3060/91.48	\neg
	Add SONET	BN 3060/90.03	Ħ
page 11	Add BERT SONET only (interfaces 1.5/6/45 Mbit/s)	BN 3060/90.34	Ħ
	Drop & Insert/Through mode	BN 3060/90.10 \[Ħ
	Mux/Demux 64k/140M	BN 3060/90.11	ī
	Mux/Demux M13	BN 3060/90.12	Ħ
		, _	
Optic	STM-0/1, 1310 nm	BN 3060/91.01	
page 12-14	STM-0/1, 1310/1550 nm	BN 3060/91.02	
	STM-0/1/4, 1310 nm	BN 3060/91.11	
	STM-0/1/4, 1310/1550 nm	BN 3060/91.12	
	STM-16, 1310 nm	BN 3060/91.51	
	STM-16, 1550 nm	BN 3060/91.50	
	STM-16, 1310/1550 nm	BN 3060/91.52	
	STM-0/1/4/16, 1310 nm Package	BN 3060/91.17	
	STM-0/1/4/16, 1550 nm Package	BN 3060/91.18	
	STM-0/1/4/16, 1310/1550 nm Package	BN 3060/91.19	
	STM-0/1/4, 1310 nm + STM-16, 1310/1550 nm Package	BN 3060/91.20	
	Optical Power Splitter	BN 3060/91.05	
CONCAT.	STM-4c ATM	BN 3060/90.91	\neg
	STM-4c Virtual Concatenation	BN 3060/90.91	╡
page 13	Jim 40 Viituut Goileatellation	DN 3000/70172 [
Jitter/	Jitter/Wander up to 155 Mbit/s Package	BN 3060/91.30	
Wander	Jitter/Wander up to 622 Mbit/s Package	BN 3060/91.31	
page 15-20	Jitter at 10 Gbit/s	BN 3060/91.60	
, -	Wander Analyzer at 10 Gbit/s (requires BN 3060/91.60)	BN 3060/91.61	
	Wander Generator at 10 Gbit/s** (requires BN 3060/91.60,	BN 3060/91.62	
	and either BN 3035/90.81 or BN 3060/91.30 or BN 3060/91.31)		
ATM	ATM Basic (PVC)	BN 3060/90.50	\neg
page 21 – 26	ATM Comprehensive (PVC/SVC)	BN 3060/90.51	Ħ
ραζε 21 20	Add ATM SONET (mappings)	BN 3060/90.53	Ħ
	Add ATM SDH (mappings)	BN 3060/90.52	Ħ
		, _	
AUTO	Automatic Test Sequencer CATS BASIC	BN 3035/95.90	
page 27	Automatic Test Sequencer CATS PROFESSIONAL	BN 3035/95.95	
Damast-	V.24/RS232 Remote Control Interface	BN 3035/91.01	\neg
Remote	GPIB/IEEE Remote Control Interface	BN 3035/91.01 E	╡
page 27	TCP/IP Remote Control Interface	BN 3035/92.11	╡
	•		\dashv
	Remote Operation	BN 3035/95.30	

^{*} This option must be ordered with the mainframe as a subsequent upgrade is not possible

^{**} Please note that the options STM-16/OC-48 or ATM comprehension and Wander Generator at 10 Gbit/s are mutually exclusive.

Specifications

The ANT-10Gig Mainframe includes:

- Mainframe, touchscreen
- STM-64 with mappings STM-1, VC-4-4c, VC-4-16c and VC-4-64c BERT
- OC-192 with mappings STS-3c, STS-12c, STS-48c and STS-192c SPE
- Mappings for STM-1: DS1, E1, DS3, E3, E4
- Electrical interfaces STM-1, E1, E3, E4
- Extended overhead analysis
- Two optical adaptors to be selected
- Ethernet and USB interface

Generator STM-64

The transmitter of the optical interface meets the specification of ITU-T G.691 (Table 5A, 5B) Application code: S-64.2b, S-64.3b, S-64.5b and I-64.2r, I-64.2, I-64.3, I-64.5, S-64.3a, S-64.5a with additional optical attenuator 1 to 3 dB and Telcordia GR-1377 (Table 4-4, 4-5, 4-6) Parameter: SR-2, LR-2 (a&c), IR-2, IR-3

Optical interface

Wavelength
Output level
Line code scrambled NRZ

Clock generator

Internal, accuracy	2 ppm
Offset ±	50 ppm
Synchronization from external signal	

Generation of STM-64 signal

compliant to ITU-T G.707
One test channel STM-1 with standard mappings or STM-4c bulk or STM-16c bulk,
others unequipped or same as test channel
Additionally generation of OC-192 signal compliant to GR-253
one test channel STS-3c or STS-12c or STS-48c SPE BERT,
others unequipped or same as test channel

Contents of STM-64 overhead bytes

For all bytes
except B1, B2, H1 to H3statically programmable
For bytes E1, E2, F1, D1 to D3
and D4 to D12 test pattern
external data via V.11
For bytes K1, K2 external data via V.11
For J0 byte

Byte sequence

m in n in p for bytes of first 16 STM-1 SOH m times (1 to 200 000 0000) byte A followed by n times (1 to 2 000 000 000) byte B sequence repetition p (1 to 65 000)

Error insertion

Error types B1, B2, MS-REI single and rat	
Burst errors: m anomalies in n periods	6
and $n = 2$ to 8001 frames or 0.2 s to 600	s

Alarm generation

Alarm types		
LOS, LOF, MS-AIS, MS-RDI,	, RS-TIM	on/off

Dynamic alarms m alarms in n frames

LOF, MS-AIS, MS-RDI	$m = 1$ to $n-1$, $n_{max} = 8000$
	or active = 0 to 60 s, passive = 0 to 600 s

Frame trigger [100]

Output voltage (open circuit)	CMOS
Connector/impedance	BNC/approx. 50 Ω

ANT-10Gig (Mainframe)

Analyzer STM-64

The receiver of the optical interface meets the specification of Telcordia GR-1377 (Table 4-4, 4-5) Parameter: SR-2, IR-2, IR-3 and ITU-T G.691 (Table 5A, 5B) Application code: S-64.2b, S-64.3b, S-64.5b, I-64.2r, I-64.2, I-64.3, I-64.5

Optical interface

Wavelength
Sensitivity
Line code scrambled NRZ
Display of optical input level15 to -8 dBm
Offset range

Demultiplexing of STM-64 signal

compliant to ITU-T G.707

Evaluation of one selectable channel

STM-1 down to the mapped tributary or STM-4c SPE or STM-16c

Additionally demultiplexing of OC-192 signal

compliant to Telcordia GR-253

Evaluation to one selectable channel STM-4c or STM-16c

Generator unit PDH/SDH

Digital outputs

Clock

Internal clock generation

Synchronisation to external signals

via 75 Ω unbalanced input, BNC jack:

- 2048 kbit/s (HDB3), 1544 kbit/s (B8ZS) or
- Receive signal

Clock outputs

– Clock output at frequency of generator signal, approx. 400 mV (when terminated into 75 Ω), BNC jack.

2048 kHz reference clock output via trigger output

STM-1 output signal

Generation of a STM-1 signal conforming to ITU-T Recommendation ${\rm G.707}$

Mappings

One selectable STM-1 mapping is included in the basic instrument. Other mappings can be added as needed.

Content of the selected container:

- Framed or unframed PDH/DSn test pattern
- PDH multiplex signal (with 64k/140M Mux/Demux chain option)
- External PDH/DSn signal (with D&I option)
- Test pattern without stuffing bits (bulk signal to O.181)

Content of non-selected containers framed PRBS 2¹¹–1

STM-1 mappings

C12 mapping (2 Mbit/s in STM-1, AU-3/AU-4)

Modes asynchronous, byte synchronous (floating)

C3 mapping (34 Mbit/s in STM-1, AU-3/AU-4)

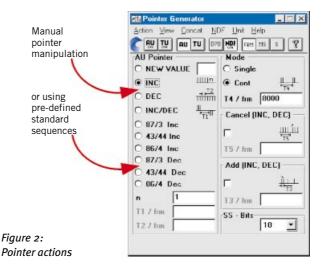
C4 mapping (140 Mbit/s in STM-1 and STS-3c)

C11 mapping

(1.5 Mbit/s in STM-1, AU-3/AU-4, TU11/TU12)

C3 mapping (45 Mbit/s in STM-1, AU-3/AU-4)

C2 mapping (6 Mbit/s unframed/Bulk in STM-1)



Generation of pointer actions (Figure 2)

Generation of pointer actions at the AU and TU levels simultaneously.

- Pointer sequences to G.783 with programmable spacing
- Pointer increment/decrement (continuously repeated)
- Single pointer
- Pointer value setting with or without NDF

Trigger types: Single or continuous repeat

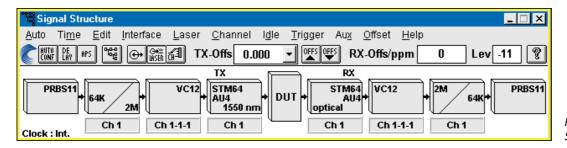


Figure 1: Signal structure

Content of SOH and POH bytes

The content of all bytes with the exception of B1/B2/B3 and H1 to H4 is programmable with any byte or a user defined byte-sequence p in m in n (p frames in m frames and the entire sequence repeated n times) can be inserted.

Bytes E1, E2, F1, F2, and byte groups D1 to D3 and D4 to D12:

- Transmission of a PRBS test pattern with bit error insertion (see test patterns)
- Insertion of an external data signal via V.11 interface (also for K1, K2 and K3)

Trace identifier

J0, J1, J2	programmable 16 byte ASCII sequence
	with CRC
J1, J2, additionally	programmable 64 byte ASCII sequence
H4 byte	4 or 48 byte sequence

Error insertion

Error types
frame alignment signal errors, MS-REI, HP-REI, LP-REI,
bit errors in test pattern, code errors (single errors)
Triggering
Single error or error ratio
for B1, B3, HP-REI, LP-REI $\dots 2 \times 10^{-4}$ to 1×10^{-10}
for bit errors 1×10^{-2} to 1×10^{-9}
Step size for mantissa and exponent
Burst error: m anomalies in n periods
For FAS, B1, B2, B3, MS-REI, HP-REI
and $n = 2$ to 8001 frames or 0.2 s to 600 s

Alarm generation

Dynamic				
Alarm types	 LOF,	MS-AIS,	MS-RDI.	AU-LOP,

	AU-AIS, HP-UNEQ, HP-RDI, HP-RDIEP,
HP-RDIES,	, HP-RDIEC, TU-LOP, TU-AIS, LP-UNEQ,
LP-RDI	, LP-RDIEP, LP-RDIES, LP-RDIEC, LP-RFI
m alarms in n frames	$m = 1$ to $n-1$, $n_{max} = 8000$
or	
t1 alarm active,	
t2 alarm passive	$\dots \dots $
-	

Static (on/off) Alarm types LOS, LOF, MS-AIS, RS-TIM, MS-RDI, AU-LOP, AU-AIS,

HP-UNEQU, HP-PLM, HP-TIM, HP-RDI, HP-RDIEP, HP-RDIES, HP-RDIEC, TU-LOP, TU-AIS, LP-UNEQ, LP-PLM, LP-TIM, LP-RDI, LP-RDIEP, LP-RDIES, LP-RDIEC, LP-RFI

PDH output signals

Signal structures for all bit rates:

- Unframed test pattern
- Framed test pattern (to ITU-T O.150); CRC-4 selectable for 2 Mbit/s

Error insertion

Error types	bit errors, FAS errors,
	code errors (single errors)
Trigger types: Single error or	
error rate	1×10^{-2} to 1×10^{-9}
Step size for mantissa and exponent	

Alarm	generation,	dynamic
A 1 a mma	trm oo	

Alarm types
Alarm generation, static (on/off)
Alarm types LOS, LOF, AIS, RDI

Test patterns

Pseudo-random bit sequences

PRBS: 2¹¹-1, 2¹⁵-1, 2²⁰-1, 2²³-1, 2¹¹-1 inv., 2¹⁵-1 inv., 2²⁰-1 inv., $2^{23}-1$ inv.

Programmable word

Length	16 bits

Receiver unit PDH/SDH

Digital inputs

Interfaces to ITU-T Recommendation G.703

75 Ω unbalanced input; adapter jack selectable from Versacon 9 adapter system

Bit rates and line codes

139 264 and 155 520 kbit/s CMI

120 Ω balanced input, Lemosa jack

Bit rate and line codes

Clock recovery pulling range ± 500 ppm

Selectable input gain

B3ZS, B8ZS, HDB3, AMI coded 15 to 26 dB

Selectable adaptive equalizers for 1544, 2048, 34 368, 44 736, 51 840, 139 264 and 155 520 kbit/s

Monitor input for STM-1 and STM-4 NRZ signals See ANT-10Gig Optical Interfaces data sheet for details.

Trigger output

75 Ω BNC connector, HCMOS signal level Pulse output for received bit errors, transmit frame trigger, transmit pattern trigger or 2048 kHz reference clock

Concatenated mappings

OC-12c/STM-4c BERT

Contiguous concatenation signal structure to ANSI T1.105.02 and G.707.

Error measurement to O.150

Test pattern PRBS-31, IPRBS-31, PRBS-23, IPRBS-23, PRBS-20, PRBS-15, IPRBS-15 Programmable word

Error insertion

Bit errors in test pattern, single error or error ratio $\dots 1 \times 10^{-2}$ to 1×10^{-9}

Error measurement and alarm detection

Bit errors and AIS in test pattern

OC-48c/STM-16c BERT

Contiguous concatenation signal structure to ANSI T1.105.02 and G.707.

Error measurement to O.150

Test pattern PRBS-31, IPRBS-31
PRBS-23, IPRBS-23

Programmable word

Error insertion

Bit errors in test pattern, single error or error ratio 1×10^{-3} to 1×10^{-9}

Alarm generation:

AU-AIS, AIS-C1...AIS-C16, AU-LOP, LOP-C1...LOP-C16

Error measurement and alarm detection:

AU-AIS, AU-LOP Bit errors

Automatic Protection Switching

Sensor: MS-AIS, AU-AIS

OC-192c/STM-64c BERT

Contiguous concatenation signal structure to ANSI T1.105.02 and G.707.

Error measurement to O.150

Test pattern PRBS-31, IPRBS-31

Programmable word

Error insertion

Error measurement and alarm detection:

AU-AIS, AU-LOP Bit errors

Automatic modes

Autoconfiguration

Automatically sets the ANT-10Gig to the input signal. The routine searches at the electrical and optical interfaces for the presence of standard PDH and STM-N signals (G.703, G.707, O.151, O.181) and the payload contents in channel 1.

Automatic SCAN function

The SCAN function permits sequential testing of all C11 or C12 channels via AU-3 or AU-4 in a SDH signal.

The ANT-10Gig receiver checks for alarms in the receive signal, the SDH structure and all channels, and for synchronization of the selected test pattern in all channels. The results (OK/not OK) for each channel are entered in a matrix. The generator runs simultaneously and can be used to stimulate the device under test.

Automatic TROUBLE SCAN function (Figure 3)

The TROUBLE SCAN function permits sequential testing of all C11 or C12 channels via AU-3 or AU-4 in a SDH signal. The ANT-10Gig receiver checks for alarms in the receive signal, the SDH structure and all channels. The results (OK/not OK) for each channel are entered in a matrix.

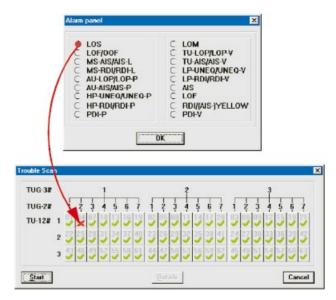


Figure 3: Trouble scan

A detailed alarm history can be displayed by selecting a channel from the matrix.

The alarm status of individual channels can be displayed following the measurement. Only the receive channels are altered during a TROUBLE SCAN.

AutoScan function (Figure 4)

This automatic "AutoScan" function allows you to rapidly check the signal structure, the mapping used and the payload – even with mixed mapped signals.

The ANT-10Gig receiver analyzes the incoming received signal and provides a clear overview of all the signals present in the composite receive signal. The variable scan depth setting allows even complex signal structures to be resolved and displayed clearly. Even Trace Identifiers are evaluated. All the displayed results can be printed out.

Automatic SEARCH function

Channel shifts in the payload may occur when measuring complex network elements, depending on the configuration of the device under test. The SEARCH function permits rapid automatic location of the test channel (C11 or C12 with defined PRBS) in the payload of a SDH signal. The ANT-10Gig receiver checks for alarms in the receive signal, the SDH structure and all channels, and for synchronization of the selected test pattern in all channels. The results (OK/not OK) for each channel are entered in a matrix. An OK result indicates that the corresponding channel contains the signal searched for. Only the receive channels are altered during a SEARCH.

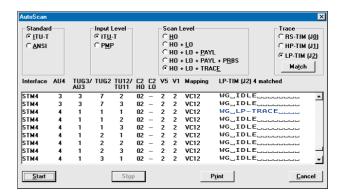


Figure 4: AutoScan

Measurement types

Error measurements

MS-REI, HP-REI, LP-REI, bit errors in test pattern, code errors

G.821:

Evaluation of PDH and SDH systems to ITU-T Recommendation

ES, EFS, SES, DM and UAS are evaluated.

Pass/fail assessment based on line length allocation of 0.1 to 100%. The SES and DM thresholds are user-settable.

Evaluation for higher bit rates (up to 140 Mbit/s) is obtained using a multiplex factor as per G.821, Annex D.

Measurements can be made using the following	lowing events:
PDH systems	bit errors, FAS2, FAS8, FAS34
	FAS140, CRC and E-bit errors
SDH systems paylo	oad bit errors (PDH and bulk),
overhead bytes E	1, E2, F2, D1 to D3, D4 to D12

G.826:

Evaluation to ITU-T Recommendation

EB, BBE, ES, EFS, SES and UAS are evaluated. Pass/fail assessment based on line length allocation of 0.1 to 100%. The SES and UAS thresholds are user-settable.

In-Service Measurement (ISM)

Simultaneous in-service measurement of near end and far end of a selected path:

- Near end: B1, B2, HP-B3, LP-B3, BIP2, FAS at 140/34/8 or 2 Mbit/s, CRC-4
- Far end: HP-REI, LP-REI, E-bit at 2 Mbit/s

Out-of-Service Measurement (OOS)

Out of service measurement using bit errors in the test pattern (for PDH and SDH).

G.828 and G.829:

Evaluation of SDH systems to ITU-T Recommendation (Figure 5)

The G.828 defines error performance parameters and objectives for international synchronous paths.

ES, EFS, SES, BBE, SEP and UAS are evaluated.

Pass/fail assessment based on line length allocation of 0.1 to 100%. The SES and UAS thresholds are user-settable. The SEP can be switched off for assessment.

The recommendation G.829 defines error performance events and block structures for SDH multiplex and regenerator sections.

M.2100:

Evaluation of PDH and SDH systems to ITU-T Recommendation

This recommendation describes requirements during line-up and maintenance (in-service).

ES, EFS, SES and UAS are evaluated.

Pass/fail assessment based on line length allocation of 0.1 to 100%. The UAS and BISO (bringing into service objectives) thresholds are user-settable.

ISM simultaneously for near end and far end of a selected path:

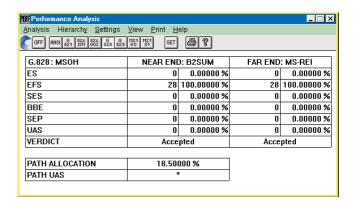


Figure 5: Performance analysis to ITU-T G.828/G.829

"Performance Information" as per ITU-T Rec. M.2120.

PDH systems, ne	ar end	bit errors, FAS2, FAS8,
		FAS34, FAS140, CRC-4
fai	end	E-bit at 2 Mbit/s
SDH systems	payload	bit errors (PDH and bulk),
	overhead bytes E1, E	2, F2, D1 to D3, D4 to D12
This operating m	ode allows application of the	he "Bringing into Service"
procedures as pe	r ITU-T Rec. M.2110 and t	he determination of

M.2101:

Evaluation of SDH systems to ITU-T Recommendation (Revision 09/99)

This recommendation describes requirements during line-up and maintenance (in-service)

ES, EFS, BBE, SEP, SES and UAS are evaluated according to the newest Revision of M.2101. Pass/fail assessment based on line length allocation of 0.1 to 100%.

The UAS and BISO (bringing into service objectives) thresholds are user-settable.

ISM simultaneously for near end and far end of a selected path or Multiplex Section:

Evaluated anomalies..... payload bit errors (TSE), B1, B2, B3 and BIP2, MS-REI, HP-REI, LP-REI

This operating mode allows application of the "Bringing into Service" procedures as per ITU-T Rec. M.2110 and the determination of "Performance Information" as per ITU-T Rec. M.2120.

Analysis of AU and TU pointer actions (Figure 6)

Display of

- Number of pointer operations: Increment, Decrement, Sum (Increment + Decrement), Difference (Increment – Decrement)
- Pointer value

Clock frequency measurement

The deviation of the input signal clock frequency from the nominal frequency is displayed in ppm.

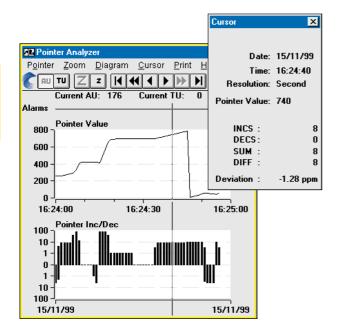


Figure 6: Graphic pointers. Display showing additional evaluation of cursor position.

Delay measurement

A delay measurement is used to line-up satellite hops, to test the maximum permitted latency in storage exchanges and cross-connect systems and to check the loop circuits of regenerators. The ANT-10Gig measures the time taken for the test pattern to be transmitted from the generator back to the receiver via the path under test. The measurement is made on the test patterns in the selected channel, in the containers (bulk or PDH) for SDH or in the selected channel at the lowest hierarchy level of PDH multiplex systems. To avoid ambiguities in the measurement, two measurement times are provided.

Measurement range
Bit rates from 8 to 155 Mbit/s 1 μs to 1 s
Bit rate 2 Mbit/s
Bit rate 64 kbit/s 100 μs to 16 s

Alarm detection

All alarms are evaluated and displayed in parallel Alarm types. LOS, OOF, LOF, MS-AIS, MS-RDI, RS-TIM, LTI, AU-AIS, AU-LOP, AU-NDF, HP-RDI, HP-UNEQ, HP-TIM, HP-PLM, AIS, RDI, LSS, TU-NDF, TU-LOP, TU-AIS, LP-UNEQ, LP-RDI, LP-RDIEP, LP-RDIES, LP-RDIEC, LP-RFI

Measurement interval

Variable	1 second to 99 days
Measurement start	. manual or automatic timer
	(user setting)
Measurement stop	. manual or automatic timer
	(user setting)

Memory for errors, pointer operations and alarms

Resolution of error events and pointers	1 s
Alarm resolution	

SOH and POH evaluation

- Display of complete SOH and POH, e.g. interpretation of APS information in K1 and K2

For the bytes E1, E2, F1, F2 and byte groups D1 to D3 and D4 to D12:

- BERT using test pattern from the generator unit
- Output of the data signal via the V.11 interface (also for K1, K2 and K3)

For the Trace Identifier

- J0	display of 16 byte ASCII sequence
– J1, J2 displa	ay of 16 or 64 byte ASCII sequence

Ring testing - APS time measurement (Figure 7)

In synchronous networks, a defined maximum switch-over time is necessary for the traffic in case of a fault.

To verify compliance with this requirement, the ANT-10Gig measures the switch-over time with 1 ms resolution.

The result can be printed.

Criteria for the time measurement TU-AIS, MS	-AIS,
AU-AIS, bit	error
Max. measurable switch-over time	2 s
Resolution	
Allowable error rate for user signal	10^{-4}

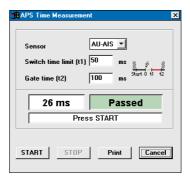


Figure 7: APS time measurement

editable value in trigger byte

Ring testing – Byte capture SOH and POH

To analyze the SOH/POH functions, it is necessary to capture individual bytes vs. time, allowing detection of errors or short-term changes with frame level precision.

The Capture function is started by a selectable trigger.

Values for a selected byte are stored and can be accessed subsequently in a table of values.

Particularly in capturing the APS sequences, the bytes (K1, K2) are displayed as an abbreviation of the standard commands.

The function also allows recording of the N1 or N2 bytes for evaluation of "Tandem Connection" information.

H4 sequences can also be analyzed very easily.

The results can be printed or exported.

Capture bytes for STM-0/1, el. & opt. all SOH/POH bytes STM-N el. & opt. all SOH/POH bytes, channel 1 except A1, A2, B1 K1, K2 200 Trigger events MS-AIS, AU-AIS, MS-RDI, AU-LOP,

Capture resolution frame precision

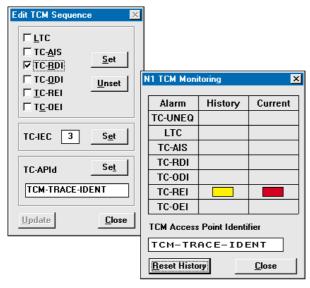


Figure 8: TCM monitor and editor

Tandem Connection Monitoring (TCM) (Figure 8)

TCM is a method used to monitor the performance of a subsection of a SDH path via the N1/N2 bytes. This is particularly useful when the path is routed via different network providers. If errors occur on an end-to-end connection, you can use TCM to determine which subnetwork the errors occurred in.

The ANT-10Gig helps to monitor the content of the N1/N2 bytes and provides users with easy interpretation of the detailed events.

TCM Byte Sequencer and Editor

This serves to test a sequential TCM process (Tandem Connection Monitoring) in the N1/N2 bytes. A sequence of 76 bytes simulating a TCM frame (equivalent frame) is generated. Individual values can be edited as binary or hexadecimal values to simulate various events for TCM evaluations.

Additionally major events may be simulated, line alarm, errors and trace identifier

Alarms	TC-ODI, TC-AIS, TC-RDI
Errors	TC-OEI, TC-IEC
Trace	TC-APID

Result display and instrument operation

Numerical display

Display of absolute and relative values for all error types

Intermediate results every 1 s to 99 min

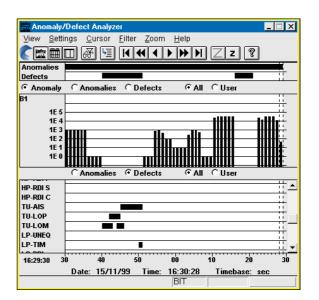


Figure 9: Histogram results display

Graphical display (histogram) (Figure 9)

Tabular display

Display of all alarm and error events with time stamp

Result printout

ANT-10Gig supports a variety of dot-matrix, inkjet and laser printers. (Windows Print Manager)

Printer interfaces

Serial	V.24/RS232
Parallel	Centronics/EPP/IEEE P 1284

Result export

Results are stored in a database and can be processed using standard PC software.

Instrument operation

ANT-10Gig is operated using the standard Microsoft $^{\circledR}$ Windows TM graphical user interface.

Operation is menu-controlled using the trackball or touchscreen. A mouse can also be connected if desired.

Application selection and storage

ANT-10Gig includes an applications library to which customer-specific applications can be added.

All applications are stored internally on the built-in hard disk drive and can be copied to any other ANT-10Gig via floppy disk or super disk

Easy to use filter functions allow quick selection of the desired application.

Touchscreen Display

Color TFT screen	10.4", 256 colors
Resolution	640 × 480 pixels (VGA standard)
The touchscreen allows very easy point and shoot operation.	

Built-in PC

ANT-10Gig uses a Pentium PC as internal controller so that standard
PC applications can also be run on the instrument.
RAM capacity
LS 120 drive
Hard disk drive 6 GB
USB interface, 10/100 Mbit Ethernet interface are included

Keyboard

Full keyboard for text input, extended PC applications and future requirements. The keyboard is protected by a fold back cover. An additional connector is provided for a standard PC keyboard.

External display connector

Simultaneous display with built-in screen	
Interface	VGA standard

PCMCIA interface

Power outage function

In the event of an AC line power failure during a measurement, ANT-10Gig saves all data. As soon as the AC line voltage is reestablished, the measurement is resumed. Previous results are retained and the time of the power failure is recorded along with other events.

General specifications

Power supply

AC line voltage,
automatic switching 100 to 127 V and 220 to 240 V
AC line frequency
Power consumption (all options fitted) max. 230 VA
Safety class to IEC 1010-1
Ambient temperature
Nominal range of use
Storage and transport range $-20 \text{ to } +70 ^{\circ}\text{C}$
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$
Weight approx. 15 kg/33 lb

Options

Electrical Interfaces at 9953 Mbit/s

BN 3060/91.48

This option must be ordered with the mainframe as a subsequent upgrade is not possible.

Generator unit

Output level (peak-peak)	400 to 600 mV
Connector/impedance	SMA/50 Ω

Receiver unit

Input level (peak-peak)	100 to	o 600 mV
Connector/impedance	S	MA/50 Ω

Clock

Frequency	99	53.28 MHz
Tx output level (peak-peak)		$. \ge 50 \text{ mV}$
Rx output level (peak-peak)		$. \ge 70 \text{ mV}$
Connector/impedance		SMA/50 Ω

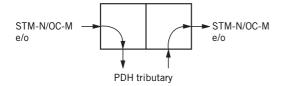
Drop & Insert

BN 3060/90.10

This option provides the following functions:

1. Generator and receiver operate independently

as mapper and demapper. The PDH signal from a selected channel is dropped from the receive signal and output to a connector. An external or internal PDH signal is inserted into the transmit signal.



2. Through mode with jitter injection, error insertion and overwriting of SOH bytes:

available for all bit rates up to 10 Gbit/s

The received signal is looped through the ANT-10Gig and re-transmitted (generator and receiver coupled).

The looped-through synchronous signal can be manipulated if required:

- Overwriting bytes in the SOH (except B1, B2, H1 to H3)
- Overwriting of B3 byte at 10 Gbit/s
- Anomaly insertion
- Defect generation by programming the SOH
- Jitter injection (Jitter options required)

64k/140M MUX/DEMUX chain BN 3060/90.11

This option provides $n\times 64$ kbit/s to 140 Mbit/s multiplex and demultiplex functions. The output signal is fed to the electrical interface and is available as payload in mappings (for STM-0 mappings please select the option "Add SONET").

Alarms and errors can be generated and analyzed.

M13 MUX/DEMUX chain

BN 3060/90.12

M13 multiplexers are used in North America in hybrid networks and synchronous system cross-connects.

This option provides $n \times DS0$ to DS3 multiplex and demultiplex functions. The output signal is fed to the electrical interface and is available as payload in mappings (requires option "Add SONET"). Alarms and errors can be generated and analyzed.

Add SONET

BN 3060/90.03

VT1.5 SPE mapping

DS1 in S1S-1 and 1.5 Mbit/s ii	n S1M-0
Modes as	synchronous, byte synchronous (floating)
Error insertion and measurem	ent
Additional error types	BIP-V, REI-V

Alarm generation, dynamic

Alarm types LOP-V, AIS-V, LOM,
UNEQ-V, RDI-V, RDIEVP, RDIEVS, RDIEVC, RFI-V, PDI-V
m alarms in n frames
or
t1 alarm active.

ti alarm active

t2 alarm passive t1 =	0 to 60 s, t2 = 0 to 600 s
-----------------------	----------------------------------

Alarm generation, static (on/off) and evaluation

Alarm generation, static (on/off) and evaluation	
Alarm types LOP-V, AIS-V, LOM	
UNEQ-V, PLM-V, TIM-V, RDI-V, RDIEV	
RDIEVS, RDIEVC, RFI-	
Alarm detection onlyNDF-'	

VT6 SPE mapping

6 Mbit/s unframed/Bulk in STS-1

STS-1 SPE mapping

DS3 in STS-1 and 45 Mbit/s in STM-0

VT2 SPE and STM-0 mapping

E1 in STS-1 and 2 Mbit/s in STM-0

Modes asynchronous, byte synchronous (floating) Error insertion and alarm generation as for VT1.5 SPE mapping.

BERT (1.5/6/45 Mbit/s)

Signal structure and interfaces for generator and receiver: Framed and unframed test patterns (6 Mbit/s unframed)

Additionally, for unbalanced digital signal input/output

Additionally, for balanced digital signal input/output

Optical Options

All the optical interfaces are intended for single-mode fibers. Acterna offers a complete line of optical test adapters. Select one test adapter each for the generator and receiver from the ordering information in this data sheet. In addition to 10 Gbit/s, ANT-10Gig provides all optical interfaces from STM-0/OC-1 to STM-16/OC-48. This includes SDH and SONET signal generation, error and alarm insertion, and SOH/TOH manipulation.

Optical Modules up to 155 Mbit/s

Optical STM-0/1, OC-1/3, 1310 nm BN 3060/91.01 Optical STM-0/1, OC-1/3, 1310 & 1550 nm BN 3060/ 91.02

Bit rate of TX and RX signal 155 520 kbit/s
additionally, for STS-1/STM-0 mappings 51 840 kbit/s
Line code scrambled NRZ

Generator unit

The generator meets the requirements of ITU-T Rec. G.957, Tables 2 and 3 (Telcordia GR-253, ANSI T1.105.06).

Classes L1.1, L1.2 and L1.3 (LR-1, LR-2, LR-3) are covered.

There are two options for ad	apting to the required wavelength:
Wavelength	1310 nm,
1310	& 1550 nm (switchable in the instrument)

Output level	0 dBm + 2/-3 dB
with 1310 & 1550 nm option 0	dBm + 2/-3.5 dB

Receiver unit

The receiver unit meets the specifications of ITU-T Rec. G.957 (Telcordia GR-253, ANSI T1.105.06) and fulfills classes S1.1 and S1.2 (IR-1, IR-2).

Wavelength range
Input sensitivity
(-34 to -8 dBm typ.)
Display of optical input level
Resolution
155 Mbit/s electrical interface
for connecting the ANT-10Gig to STM-1/STS-3 monitor points
Line code scrambled NRZ
Input voltage (peak-peak) 0.2 to 1 V
Unbalanced input
Connector/impedance SMA/50.0

Optical Modules up to 622 Mbit/s

Optical STM-0/1/4, OC-1/3/12, 1310 nmBN 3060/91.11 Optical STM-0/1/4,

OC-1/3/12, 1310 & 1550 nm BN 3060/91.12

Bit rate of TX and
RX signal 155 520 kbit/s, 622 080 kbit/s
additionally, for STS-1/STM-0 mappings 51 840 kbit/s
Line code scrambled NRZ

Generator unit

The generator meets the requirements of ITU-T Rec. G.957, Tables 2 and 3 (Telcordia GR-253, ANSI T1.105.06).

Classes L1.1, L1.2, L1.3, L4.1, L4.2 and L4.3 (LR-1, LR-2, LR-3) are covered.

There are two options for adapting to the required wavelength:
Wavelength
1310 & 1550 nm (switchable in the instrument)
Output level
with 1310 & 1550 nm option 0 dBm +2/-3.5 dB

Generation of STM-4 TX signal

In instruments with STM-1 mappings

The STM-4 TX signal consists of

- four identical STM-1 tributary signals (AU-4), or
- one internally generated STM-1 tributary signal with the other three tributaries filled with UNEQ.

Generation of OC-12 TX signal

In instruments with STS-1 mappings

The OC-12 TX signal consists of

- one internally generated STS-1 tributary signal with the other 11 tributaries filled with UNEQ or
- one internally generated STS-3c tributary signal with the other three tributaries filled with UNEQ.

with STS-3c mapping option or ATM Basic Option BN 3060/90.50

Contents of the STM-4/OC-12 overhead bytes

For all bytes except B1, B2 and H1 to H3:

 The content of each byte is statically programmable or a user defined byte-sequence p in m in n (p frames in m frames and the entire sequence repeated n times) can be inserted.

For the E1, E2, F1 bytes and the DCC channels D1 to D3 and D4 to D12:

- Transmission of a test pattern with bit error insertion (see mainframe for pattern selection)
- Insertion of an external data signal (via the V.11 interface)

For the K1, K2, N1, N2 bytes:

- Insertion of the data signal via the V.11 interface

For the J0 bytes:

- Transmission of a 16-byte sequence, with CRC

Error insertion

Error types
additionally, for STM-4
for OC-12 REI-L
Triggering Single errors or error ratio $2\times10^{-3} \text{ to } 1\times10^{-10}$ for B1 parity errors $2\times10^{-4} \text{ to } 1\times10^{-10}$
Burst error: m anomalies in n periods For FAS, B1, B2, B3, REI-L, REI-P $m=1$ to 4.8×106 and $n=2$ to 8001 frames or 0.2 s to 600 s

Alarm generation, dynamic

Alarm types for STM-4	LOF, MS-AIS, MS-RDI
for OC-12	LOF, AIS-L, RDI-L
m alarms in n frames	$m = 1 \text{ to } n-1, n_{max} = 8000$
or	
t1 alarm active, t2 alarm passive	$t1 = 0$ to 60 s,
	t2 = 0 to 600 s

Alarm generation, static (on/off)

Alarm types	LOS, LOF
additionally, for STM-4	MS-AIS, MS-RDI, RS-TIM
for OC-12	AIS-L, RDI-L, TIM-L
Insertion on/off	

The receiver unit meets the specifications of ITU-T Rec. G.957 (Telcordia GR-253, ANSI T1.105.06) and fulfills classes S1.1, S1.2, S4.1, S4.2, L4.1, L4.2 and L4.3 (IR-1, IR-2, LR-1, LR-2, LR-3).

The ANT-10Gig demultiplexes one selectable STM-1 or STS-3c/STS-1 tributary from the STM-4 or OC-12/OC-3 RX signal and feeds it to the internal processor for evaluation.

Measurement types

Overhead evaluation

 Display of the complete overhead of a selectable STM-1/STS-1/STS-3c signal

For the E1, E2, F1 bytes and the DCC channels D1 to D3 and D4 to D12:

- BERT using a test pattern from the generator unit
- Output of the data signal via the V.11 interface

For the K1, K2, N1, N2 bytes:

- Data signal output via the V.11 interface

For the J0 byte:

- Display of 15-byte sequences in ASCII.

155/622 Mbit/s electrical interface

For connecting the ANT-10Gig to STM-1/OC-3 and STM-4/OC-12 monitor points

Line code scrambled 1	√RZ
Input voltage (peak-peak) 0.2 to	1 V
Coaxial input	
Connector/impedance	Ω 0

Concatenated Mappings

Only in conjunction with BN 3060/90.90 or BN 3060/90.91

Option OC-12c/STM-4c

Virtual Concatenation BN 3060/90.92

Signal structure

STM-4 to ITU-T G.707

Virtual concatenation with 4 AU-4 pointers

Generation of pointer actions

Manipulations on pointer #1 as in basic data sheet Setting of delta values for pointers #2, #3, #4

Pointer analysis

For pointer #1	as in basic data sheet
Delta values (maximum, minimum)	$\dots \dots \pm 40$
	for pointers #2, #3, #4

POH generation/analysis

POH #1 as in basic data sheet
POH #2, #3, #4 static setting of all bytes except B3

Automatic B3 generation for VC-4 #1, #2, #3, #4

Option OC-12c/STM-4c ATM-Testing

BN 3060/90.91

Only in conjuction with BN 3060/90.50 and BN 3060/91.11 or BN 3060/91.12

See chapter "ATM options" for further details.

Optical Modules 2488 Mbit/s

Optical STM-16, OC-48, 1310 nm BN 3060/91.51
Optical STM-16, OC-48, 1550 nm BN 3060/91.50

Optical STM-16, OC-48,

1310/1550 nm switchable BN 3060/91.52

One 2.5 Gbit/s module can be fitted in the extension slot of the ANT-10 Gig. $\,$

The optical interfaces meet the specifications of ITU-T Recommendation G.957 (Table 4) and Telcordia TA-NWT-000253 I.6 (Table 4–9, 4–10). Classes S-16.2, L-16.2, L-16.3 (ITU-T) or IR-2, LR-2, LR-3 (Telcordia) are fulfilled at 1550 nm; classes S-16.1, L-16.1 (G.957) or IR-1, LR-1 (Telcordia) are fulfilled at 1310 nm.

Generator

Optical interfaces

Wavelengths	1310 nm, 1550 nm
or 1310/	1550 nm switchable
Output level at 1310 nm and 1550 nm	0.0 dBm + 0/-2 dB
Line code	scrambled NRZ

Electrical interfaces

Line code scra	ambled NRZ
Output voltage (peak-peak)	≥0.6 V
Connector/impedance	. SMA/50 Ω

Clock generator

Internal, accuracy ±	2 ppm
Offset ± 5	50 ppm
Synchronization from external signal as for mainframe	

Generation of STM-16 TX signal

In instruments with STM-1 mappings

The STM-16 signal consists of one or more intern. generated tributaries plus several tributaries filled with UNEQ (or non-specific UNEQ)

- 16 identical STM-1
- One STM-1 tributary and $15 \times$ UNEQ/non specific
- 4 identical STM-4c (Option BN 3060/90.90 required)
- One STM-4c tributary (Option BN 3060/90.90 required) and 3 × UNEQ/non specific

Generation of OC-48 TX signal

In instruments with STS-1/STS-3c mappings

The OC-48 signal consists of one or more intern. generated tributaries plus several tributaries filled with UNEQ (or non-specific UNEQ)

- 48 identical STS-1
- One STS-1 tributary and $47 \times \text{UNEQ/non specific}$
- 16 identical STS-3c (Option BN 3060/90.02 required)
- One STS-3c tributary (Option BN 3060/90.02 required) and 15 × UNEQ/non specific
- 4 identical STS-12c (Option BN 3060/90.90 required)
- One STS-12c tributary (Option BN 3060/90.90 required) and 3×UNEQ/non specific

Contents of STM-16/OC-48 overhead bytes

For all bytes except B1, B2 and H1 through to H3:

The contents of the bytes in all SOH/TOH are statically programmable

For the bytes E1, E2, F1 and the DCC channels D1 to D3 and D4 to D12:

- Transmission of a test pattern and bit error insertion (see mainframe for pattern selection)
- Insertion of an externally-generated data signal (via V.11 interface)

For the K1, K2, N1, N2 bytes:

- Insertion of an external data signal via the V.11 interface

For the J0 byte:

- Transmission of a 16-bit sequence with CRC

Error insertion

Error types	
Single error or error rate B1	
B2 1×10^{-10} to 2×10^{-3}	
additionally, for STM-16 MS-REI	
for OC-48 REI-L	
Single error or error rate 1×10^{-10} to 2×10^{-3}	

Alarm generation, dynamic

Alarm types for STM-16	LOF, MS-AIS, MS-RDI
for OC-48	LOF, AIS-L, RDI-L
m alarms in n frames	. $m = 1$ to $n-1$, $n_{max} = 8000$
or	
t1 alarm active, t2 alarm passive	$t1 = 0$ to 60 s.

Alarm generation, static (on/off)

Alarm types			 		LOS, L	OF
additionally,	for STM-16	·	 	MS	-AIS, MS-F	RDI
	for OC-48		 		AIS-L, RD	I-L

Receiver

Optical interfaces

Wavelength
Line code scrambled NRZ
Sensitivity
Input overload>–8 dBm
Display of optical input level
Range
Resolution 1 dF

Electrical interfaces

Line code scramb	oled NRZ
Input voltage (peak-peak)).3 to 1 V
Connector/impedance	$MA/50 \Omega$

A selectable STM-1, STS-1 or STS-3c channel is fed to the internal evaluation circuits by demultiplexing from the input signal.

Error measurement

Error types	. B1 parity error, MS-REI,
	B2 parity sum error over
all STM	1-1/STS-1/STS-3c channels
Evaluation (bit/block errors)	error rate, count
Error event resolution	$\dots \dots $

Alarm detection

Alarm typs	LOS, LOF, OOF
additionally, for STM-16	MS-AIS, MS-RDI, RS-TIM
for OC-48	AIS-L, RDI-L, TIM-L
Alarm event resolution	100 ms

SOH/TOH evaluation

Display of complete overhead

For the bytes E1, E2, F1 and the DCC channels D1 to D3 and D4 to D12:

- BERT using test pattern from generator unit
- Output of the data signal via the V.11 interface

For the K1, K2, N1, N2 bytes:

- Data signal output via the V.11 interface

For the J0 byte:

- Display of 15-byte sequences in ASCII format

DWDM laser

Optical STM-64, OC-192, 15xy nm Special DWDM lasers to G.692 BN 3060/91.49

Lasers with precisely defined wavelengths in the 1550 nm range are used specifically for DWDM applications. The ANT-10Gig can be fitted with a selected laser source conforming to ITU-T G.692 for such applications.

Further options

t2 = 0 to 600 s

Optical Power Splitter (90%/10%) BN 3060/91.05

The optical power splitter is built into the ANT-10Gig. Three optical test adapters are required to operate it, please indicate your choice.

The optical power splitter provides an optical monitor point. The input signal is passed through to the output transparently.

Jitter and Wander Options

As an alternative to the STM-16/OC-48 option, jitter applications up to 622 Mbit/s or wander at 10 Gbit are possible with the ANT-10Gig. The modules are optimized for compliance with the latest standard (O.172) and assure reliable jitter and wander measurements, useful when analyzing pointer jitter in 10 Gbit/s systems, for example. ANT-10Gig is particularly adept at wander analysis. The graphical MTIE wander analyses require no external computing resources and allow rapid verification of the synchronicity of a SDH network. Jitter/wander components are available for all built-in bit rates up to 622 Mbit/s and for 10 Gbit/s.

Standards

Jitter generation and jitter/wander analysis are in accordance with:

- Telcordia GR-253, GR-499, GR-1244
- ANSI T1.101, T1.102, T1.105.03, T1.403, T1.404, T1.105.09
- ITU-T G.783, G.823, G.824, G.825, O.171, O.172
- ETSI ETS 300 462-1 to -6, ETS 300 417-1-1, EN 302 084

0.172 Jitter/Wander up to 155 Mbit/s BN 3060/91.30

Jitter generator

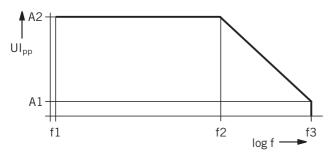
Fully complies with or exceeds the requirements of ITU-T O.172.

Bit rates

Generates jitter at all bit rates included in the mainframe configuration up to 155 520 kbit/s.

TX signals all test patterns and frame structures included in the mainframe configuration

Built-in modulation generator (sinewave) 0.1 Hz to 5 MHz External modulation 0 Hz to 5 MHz Jitter amplitude up to 64 UI



Clock rate/kHz	A1	A2	f1/Hz	f2/Hz	f3/kHz															
1 544				625	80															
2 048			1 560	200																
6 312				940	120															
8 448				6 250	800															
34 368	0.5	64	64	64	64 0.1	64	64	64	64	64	64	64	64	64	64	64	64	0.1	27 k	3 500
44 736	0.5											0.1	35 k	4 500						
51 840											27 k	3 500								
139 264						39 k	5 000													
155 520				39 k	5 000															
622 080 *	1.0	256		20 k	5 000															

* Requires option BN 3060/91.31

Modulator input

Error limits	 as per O.172
Voltage required	 0 to 2 Vpp
75 Ω , BNC socket	

Jitter Analyzer

Jitter measurement at all bit rates included in the mainframe configuration up to 155 520 kbit/s.

Built-in filters

High-pass filters	0.1, 2, 4, 10, 20, 40, 100, 200, 400,
	500, 700 Hz,
	1, 3, 8, 10, 12, 18, 20, 30, 65, 80, 250 kHz
Low-pass filters	40, 60, 100, 400, 800, 1300, 3500,
	5000 kHz
Filter characteristics	as per 0.172

Measurement ranges
Peak-peak
Range I, Resolution 0 to 1.6 UIpp, 1 mUIpp
Range II, Resolution 0 to 20 UIpp, 10 mUIpp
Range III, Resolution 0 to 200 UIpp, 100 mUIpp
RMS
Range I, Resolution 0 to 0.8 UIpp, 1 mUIpp
Range II, Resolution 0 to 10 UIpp, 10 mUIpp
Range III, Resolution 0 to 100 UIpp, 100 mUIpp
Measurement accuracy as per O.172

Demodulator output

Demodulator output	
75 Ω , BNC socket	
Range I (0 to 1.6 UIpp) 1 V/	/UIpp
Range II (0 to 20 UIpp)	/UIpp
Range III (0 to 200 UIpp) 0.01 V	/UIpp

Wander Generator

Fully complies with or exceeds the requirements of ITU-T O.172

Wander generation at all implemented bit rates up to 155 Mbit/s according to the equipment level of the instrument. Amplitude range up to 200 000 UI Frequency range $\,$ $\,$ 10 μHz to 10 HzAccuracy as per O.172 Resolution 1 μHz

Wander Analyzer

Fully complies with or exceeds the requirements of ITU-T O.172

For all bit rates up to 155 Mbit/s according to the equipment level of the instrument.

Other sampling rates in addition to the 30/s rate are available for detailed analysis versus time:

Sampling rate – low-pass filter

Samping rate – low-pass	IIItei –
test duration	1/s - 0.1 Hz - 99 days
	30/s - 10 Hz - 99 h
	60/s - 20 Hz - 99 h
	300/s - 100 Hz - 5000 s
Amplitude range	± 1 ns to ± 1 μs
Measurement accuracy .	as per O.172

Accessory: "Standard Frequency Source" for wander applications, see end of chapter

O.172 Jitter/Wander up to 622 Mbit/s BN 3060/91.31

Jitter	Generator
T*	1 1

 Jitter modulation of STM-4 TX signals.

 Built-in modulation generator (sinewave)
 0.1 Hz to 5 MHz

 External modulation
 0 Hz to 5 MHz

 Jitter amplitude
 up to 256 UI

Jitter modulation of externally-generated signals in Through mode

Externally-generated signals can be jittered in Through mode when the D&I option is included.

This applies to all bit rates included in the mainframe configuration at the appropriate electrical and optical interfaces.

Built-in modulation generator (sinewave) 0.1 Hz to 5 MHz External modulation 0 Hz to 5 MHz Jitter amplitude as for jitter generator in UIpp

Jitter Analyzer

Measurement range

Peak-peak0 to 6.4 UIpp, 1 mUIppRange I, Resolution0 to 6.4 UIpp, 1 mUIppRange II, Resolution0 to 80 UIpp, 10 mUIppRange III, Resolution0 to 800 UIpp, 100 mUIpp

RMS

Demodulator output

Wander Generator

Fully complies with or exceeds the requirements of ITU-T O.172

Bit rates

Wander generation at all implemented bit rates up to 622 Mbit/s according to the equipment level of the instrument.

Wander Analyzer

Fully complies with or exceeds the requirements of ITU-T O.172

Other sampling rates in addition to the 30/s rate are available for detailed analysis versus time:

Sampling rate – low-pass filter –

Reference signal input

Frequencies	1.544, 2.048, 5, 10 MHz
Bit rates	1.544, 2.048 Mbit/s
Balanced 110 Ω connector	Bantam

Clock input voltage (sine or square wave) 1.0 to 6.5 Vpp HDB3/B8ZS input voltage \pm 3 V \pm 10%
Coaxial 75 Ω connector
(sine or square wave) 1.0 to 5 Vpp HDB3/B8ZS input voltage ± 2.37 V $\pm 10\%$
Accessory: "Standard Frequency Source" for wander applications, see end of chapter

0.172 Jitter/Wander at 9953 Mbit/s

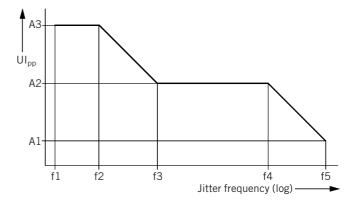
 Jitter at 9953 Mbit/s
 BN 3060/91.60

 Wander Analyzer at 9953 Mbit/s
 BN 3060/91.61

 Wander Generator at 9953 Mbit/s
 BN 3060/91.62

Jitter Generator

Fully complies with or exceeds the requirements of ITU-T O.172.



Amplitude in UIpp		Frequency in Hz					
A1	A2	A3	f1	f2	f3	f4	f5
0.5	20	3200	0.1	12.5	2 k	2 M	80 M

Modulator input

75 Ω , BNC socket

Modulation frequency0.1 Hz to 80 MHzInput voltage range0 to 2.0 VppError limitsas per ITU-T O.172

Jitter Analyzer

Bit rate 9 953 280 kbit/s

Measurement ranges

Peak-peak

Range I, Resolution ... 0 to 4 UIpp, 1 mUIpp
Range II, Resolution ... 0 to 40 UIpp, 10 mUIpp
Range III, Resolution ... 0 to 3200 UIpp, 100 mUIpp

RMS

Range I, Resolution ... 0 to 2 UIpp, 1 mUIpp
Range II, Resolution ... 0 to 20 UIpp, 10 mUIpp
Range III, Resolution ... 0 to 1600 UIpp, 100 mUIpp
Measurement accuracy ... as per O.172

Built-in filters

High mass filtons

as per ITU-T O.172, G.825, G.813, Telcordia GR-1377, ANSI T1.101, T1.105.03

rigii-pass litters 10 kmz, 12 kmz, 20 kmz, 50 kmz and	i 4 MITIZ
Low-pass filters	80 MHz
The high-pass filters can be switched off.	
Frequency range without high-pass filter	
Measurement range I	100 Hz
77	10.11

10 kHz, 12 kHz, 20 kHz, 50 kHz, and 4 MHz

Measurement range I	100 Hz
Measurement range II	10 Hz
Measurement range III	10 Hz

Demodulator output

75 Ω , BNC socket

Output voltage

Surput voltage	
Measurement range I (0 to 4 UIpp) 0.5 V/	UIpp
Measurement range II (0 to 40 UIpp) 50 mV/	UIpp
Measurement range III (0 to 3200 UIpp) 0.625 mV/	UIpp

Wander Generator

Requires option BN 3035/90.81 or BN 3060/91.30 or BN 3060/91.31 Fully complies with or exceeds the requirements of ITU-T 0.172.

Bit rate	9 953 280 kbit/s
Amplitude range	0.1 UI to 320 000 UI
Frequency range	10 μHz to 10 Hz
	as per O.172
	1 μHz

Wander Analyzer

Fully complies with or exceeds the requirements of ITU-T O.172

Other sampling rates in addition to the 30/s rate are available for detailed analysis versus time:

Sampling rate - low-pass filter -

test duration		1/s – 0.1 Hz – 99 days
		30/s - 10 Hz - 99 h
		60/s - 20 Hz - 99 h
	3	300/s – 100 Hz – 5000 s
Amplitude rai	nge	± 1 ns to ± 1 μs
Measurement	accuracy	as per O.172

Reference signal input

Frequencies	
Balanced 110 Ω connector Clock input voltage	
(sine or square wave)	

Coaxial 75 Ω connector Clock input voltage

For "Standard Frequency Source" accessory for wander applications, see end of section

Jitter Analysis

occurs (phase tolerance to O.172).

Current values (continuous measurement) Peak jitter value in UIpp Positive peak value in UI+p Negative peak value
Maximum value (gated measurement) Maximum peak jitter value in UIpp Maximum positive peak value in UI+p Maximum negative peak value in UI-p
Result averaging (switchable) 1 to 5 s The ANT-10Gig retains phase synchronicity even when pointer jitter

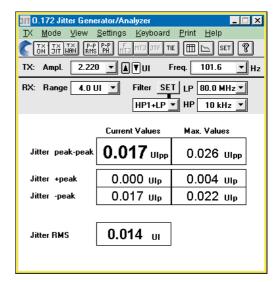


Figure 10: Jitter peak to peak/RMS measurement

Phase hits

The instrument detects when the programmable threshold for positive and negative jitter values is exceeded.

The result indicates how often this threshold was exceeded.

Setting range for positive and negative thresholds

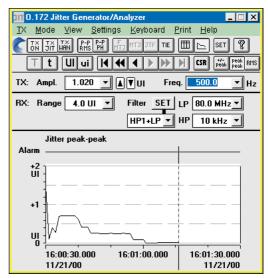


Figure 11: Jitter versus time display

Jitter versus time (Figure 11)

This function is used to record variations of jitter with time.

It allows the positive and negative peak values or peak-to-peak values to be displayed versus time.

Measured values have one second resolution. Measurement duration is up to 99 days.

By simultaneously evaluating alarms and errors, corellations between events can be quickly identified.

Clock jitter measurement

The ANT-10Gig can also measure the jitter on the clock signals (square-wave) at standard bit rates. All built-in bit rates with electrical interfaces up to 155 Mbit/s can be measured.

RMS measurement

T1.105.03, GR-253, GR-499, G.958 (or G.783 rev.)

The RMS value is measured on-line and displayed in UI. The peak jitter and RMS values can be displayed simultaneously; a graph versus time is available for long-term analysis. An RMS filter preset is available.

Wander Analysis

Time Interval Error (TIE)

MTIE is additionally determined as a continually updated numerical value.

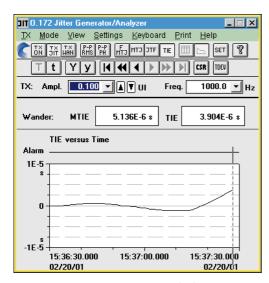


Figure 12: On-line wander testing (TIE)

To prevent data loss or premature termination of long term measurements, the ANT-10Gig checks the remaining space on the hard disk before the start of the measurement. If necessary, the selected measurement time can be adjusted.

The TIE values are recorded and are then available for subsequent off-line MTIE/TDEV evaluations. The values are also saved in .csv format for documentation or further analysis.

MTIE/TDEV Off-line Analysis Evaluation

This software provides extended off-line statistical analysis facilities for the results of wander measurements.

TIE values results obtained using the ANT-10Gig are analyzed according to ANSI T1.101, Telcordia GR-1244, ETSI ETS 300 462, EN 302 084, ITU-T O.172, G.810 to G.813.

Network synchronization quality is presented graphically using the MTIE (Maximum Time Interval Error) and TDEV (Time DEViation) parameters. To ensure correct assessment, the tolerance masks for PRC (Primary Reference Clock), SSU (Synchronization Supply Unit), SEC (Synchronous Equipment Clock) or PDH can be superimposed.

The results and masks can be printed out with additional user-defined comments.

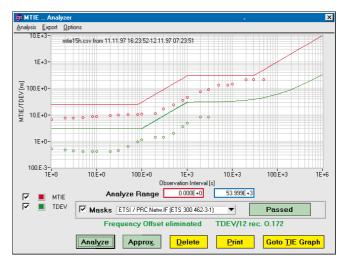


Figure 13:
Display of MTIE/TDEV results and comparison against masks

This software allows several TIE results to be displayed simultaneously. Decisive details during long term measurements disappear in the multitude of results. An effective zoom function is available for detailed wander characteristic analysis.

Result printout and export

The results can be printed out and stored internally or on floppy disk. The file format allows further processing using standard PC software.

Frequency offset and frequency drift rate (ANSI T1.101)

To ensure reliable operation when a clock source is in holdover mode, the frequency characteristics must not exceed specific deviation limits relative to an absolute reference source.

To verify this data, the ANT-10Gig determines the following over the selected measurement interval:

Frequency offset	in ppm
Frequency drift rate	in ppm/s

MRTIE - Relative MTIE (G.823 and EN 302 084)

If the reference is unavailable (too far away) when analyzing the wander of asynchronous signals, the MTIE analysis may have a superimposed frequency offset.

This offset depends on the difference between the signal and local reference clocks.

The MRTIE measurement subtracts the frequency offset from the result so that the "actual" wander characteristic is shown.

Accessory for wander analysis
Standard frequency source see end of chapter

Automatic Measurements

The following automatic measurements can be run for all standard bit rates and interfaces included in the mainframe configuration (electrical/optical) up to 2488 Mbit/s.

Automatic determination of selective Jitter Transfer Function, JTF

Telcordia GR-499, GR-253, ANSI T1.105.03, ITU-T G.958

The Jitter Transfer Function indicates the ratio of the jitter amplitude at the output of the device under test to that at the input at various frequencies.

This determines whether the device under test reduces or amplifies input jitter and at which frequencies. After a calibration measurement to minimize intrinsic errors, the ANT-10Gig outputs a pre-selected jitter amplitude at various frequencies and measures selectively the jitter amplitude at the output of the device under test.

The ratio of the amplitudes in dB is the Jitter Transfer Function.

The preselected amplitudes correspond to the mask for maximum permitted input jitter. The jitter frequencies and amplitudes can also be edited. The calibration values can be saved and used again for other measurements.

Additional measurement mode

- Transfer MTJ results:

An MTJ measurement is first performed. The measured amplitude values can then be used automatically as generator values for the JTF measurement.

The results can be displayed in tabular and graphical form. The graphical display includes the standard tolerance masks specified in T1.105.03 and GR-253 or G.735 to G.739, G.751, G.758. The distance of the measurement points from the tolerance masks indicates the degree to which the device under test meets the requirements of the standard.

Tolerance mask violations during the measurement are indicated in the numerical table.

Freely programmable tolerance masks

The existing tolerance masks for the ANT-10Gig can be altered as required to suit requirements that do not conform to specific standards. The new values selected for jitter frequency and jitter gain/loss are stored when the application is saved.

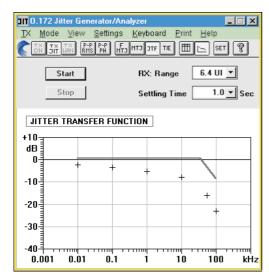


Figure 14: Jitter transfer testing results

Automatic limit testing of Maximum Tolerable Jitter (Fast Maximum Tolerable Jitter F-MTJ)

ANSI T1.403, T1.404, T1.105.03, Telcordia GR-253, GR-499, ITU-T G.823, G.824, G.825, G.958

This extremely fast measurement tests the device under test for conformance to the standard tolerance mask limits for maximum tolerable jitter.

Detection criteria	TSE (bit error),
	code error, B2, B3, REI, RDI
Error threshold	0 to 999 999 errors
Settling time	0.1 to 99.9 s

The editable frequency/amplitude values are set sequentially and the test pattern monitored for the permitted bit error count by the receiver.

The result of each measurement is shown in a table as the status message "OK" or "FAILED".

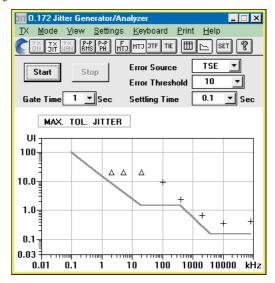


Figure 15: Maximum Tolerable Jitter testing

Automatic determination of Maximum Tolerable Jitter, MTJ

ANSI T1.403, T1.404, T1.105.03, Telcordia GR-253, GR-499, ITU-T G.823, G.824, G.825, G.958

The ANT-10Gig automatically determines the maximum jitter amplitude tolerated by the device under test at each jitter frequency. Jitter frequencies 20 freely selectable frequencies Detection criteria TSE (bit error), code error, B2, B3, REI, RDI Error threshold 0 to 999 999 errors Settling time 0.1 to 99.9 s Gating time 1 to 999 s

The maximum permissible jitter amplitude is determined precisely and quickly using a successive method.

The ANT-10Gig determines the exact limit value.

The method is derived from long experience in the performance of jitter tolerance tests and is recognized by leading systems manufacturers.

The frequency/amplitude result pairs can be displayed in tabular and graphical form.

The graphical display includes the standard tolerance masks. The distance of the measurement points from the tolerance masks indicates the degree to which the device under test meets the requirements of the standard.

Tolerance mask violations during the measurement are indicated in the numerical table.

Freely programmable tolerance masks

The existing tolerance masks for the ANT-10Gig can be altered as required to suit requirements that do not conform to specific standards. The new values selected for jitter frequency and amplitude are stored when the application is saved.

Automatic pointer sequences for analyzing combined

jitter (available with CATS Test Sequencer option)

Among other things, T1.105.03 defines various pointer sequence scenarios for testing combined jitter (mapping and pointer jitter) at network elements.

These sequences are normally selected manually and the jitter measured. ANT-10Gig allows simple automation of these sequences. The entire sequence is started and the maximum pointer jitter determined with a single key press. This saves considerable time spent in setting up the test and executing the measurement.

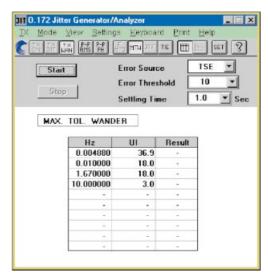


Figure 16: Maximum tolerable wander result display

Automatic limit testing of Maximum Tolerable Wander, MTW

ITU-T G.823, G.824

The ANT-10Gig tests the device under test for conformance to the standard tolerance mask limits for maximum tolerable wander.

Measurement points	up to 10 frequency/amplitude values
Detection criteria	TSE (bit error), alarms
Frequency range	10 μHz to 10 Hz, step 1 μHz
Amplitude range	0.1 to 200 000 UI, step: 0.1 UI

The result of each measurement is shown in a table with an "OK" or "FAILED" message.

Accessory

Acterna TSR-37 Rubidium Timing Signal Reference

DA 3700/00

The TSR-37 is a powerful reference source to quickly measure and test the synchronization quality of PDH/SDH/SONET digital networks. MTIE and TDEV measurements for up to 1000 seconds can be easily performed without a GPS reference. Coupled with the optional GPS-FC, the range of observation time can be largely extended to meet specific requirements.

Provides the reference clock for wander analysis using the ANT-10Gig.



- PDH/SDH/SONET Wander measurement source
- Accuracy at 25 °C: $+5 \times 10^{-11}$ without GPS $< 1 \times 10^{-11}$ with GPS
- 12 outputs, framed and unframed: 5 MHz, 10 MHz, 2.048 kHz, 1.544 kHz, E1, T1
- Compact, robust & lightweight
- External autocalibration input
- Input for GPS or Cesium reference

See Acterna TSR-37 data sheet for details.

ATM Options

With its ATM options, ANT-10Gig enables commissioning tests on newly installed ATM links. The major error- and delay-related performance parameters can be quickly and reliably verified in this manner. Using the flexible cell generator, policing functions can be easily checked. Bit error analyses and alarm flow diagnostics allow a fast assessment of whether links are working properly.

ATM cells can be generated for all bit rates up to STM-4c/OC-12c.

ATM Basic

BN 3060/90.50

General

Adjustable test channel from 0 to 150 Mbit/s

In ATM network elements, user channels are monitored with the UPC (usage parameter control). The sensors of the control instance can be quickly checked if the bandwidth of a test channel exceeds the set threshold in the network element. For all measurements, the test channel in the ANT-10Gig is set on-line. Settings are made directly with a control (Figure 18) which shows the bandwidth in Mbit/s, Cells/s or %. This makes it easy to simulate CBR (Constant Bit Rate) sources.

For each interface, the load setting has a range from 0.01% to 100%. This corresponds to the load conditions which can occur in the real world

Load profiles

A test channel can be generated with typical load profiles in order to stress network elements or simulate source profiles. In burst mode, for example, the burst load, burst length and burst period parameters can be used to simulate a video signal whose key figures correspond to a real-life signal.

Background load generator

To make a real-time measurement under loaded conditions, additional background load can be simulated to supplement the test channel (foreground traffic). The ATM channels are defined using an editor. The user specifies the repetition rate of the load cell and a sequence of empty cells. Load channels can be transmitted continuously as a sequence. The load generator can also be used separately with the test channel switched off. In this case, the channels and profiles can be user-specified.

Determining Cell Delay Variation

The ANT-10Gig includes very powerful tools for measuring delay parameters. Once a precise measurement has been made, subsequent measurements usually require only a low-resolution display to allow rapid pass/fail assessment. Delay values are displayed by the ATM Traffic Analyzer as a histogram with a minimum class width equal to 160 ns (maximum 335 ms).

As a result, delay fluctuations are shown graphically with the same resolution. An adjustable offset can be used to maintain measurement accuracy even if the delay values are high, e.g. over international links.

F4/F5 OAM alarm flow

In accordance with I.610 and the ATM forum standard, the status of ATM paths and channels is transmitted in the OAM cell stream (fault management). The ANT-10Gig generates the alarms VP-AIS, VC-AIS or VP-RDI, VC-RDI for the foreground channel. The receiver simultaneously detects alarms and error messages in the channel and path.

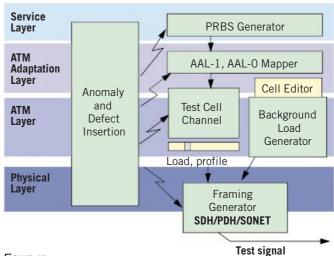


Figure 17: ATM-BERT generator configuration

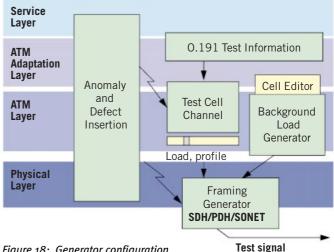
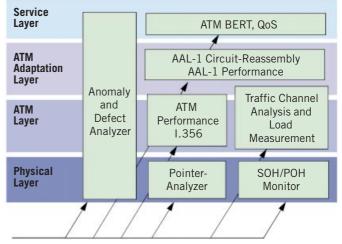


Figure 18: Generator configuration for performance measurement



Test signal

Figure 19: Analyzers in the ANT-10Gig - A hierarchical overview

The ATM module comprises:

- Generation and analysis of ATM cell streams
- ATM layer cell transfer performance as per ITU-T I.356, O.191
- AAL-1 segmentation/reassembly for circuit emulation
- STM-1/STS-3c with C4 ATM mapping, ITU-T G.707, ANSI T1.105/107
- F4/F5 fault management OAM flow for AIS and RDI as per ITU-T I.610, ATM forum UNI 3.1

Generator unit

		155.520 Mbit	
Cell scrambler X ⁴³ +1 ((ITU-T)	. can be switched on and o	off

Test cell channel

Adjustable from 0 to 149.760 Mbi	t/s
Header setting edit	tor
Load setting in Mbit/s, Cells/sec,	%

Test cells, payload pattern

AAL-0, Pseudo-Random
Bit Sequences (PRBS)
AAL-1, Pseudo-Random
Bit Sequences (PRBS)
Programmable word, length
Test pattern for ATM performance analysis, with
Sequence number
Time stamp
Error correction

Load profiles

Equidistant, setting range	1 to 10 000 cell times
Constant Bit Rate (CBR), setting range .	0.01% to 100%
Variable Bit Rate (VBR), settings	
Peak cell rate	1% to 100%
Mean cell rate	1% to 100%
Burst size	1 to 1023 cell times
Burst period	2 to 32 767 cell times

Error insertion

Physical layer as with ANT-10Gig basic instrument ATM layer, AAL:

Correctable and non-correctable header errors

- AAL-0, cell payload bit errors
- AAL-1, sequence number errors
- AAL-1, SAR-PDU bit errors
- AAL-1 SNP, CRC errors
- AAL-1 SNP, parity errors

Triggering single errors, error ratio, n errors in m cells

Alarm generation

Physical layer as with basic instrument, also:
Loss of Cell DelineationLCD
ATM layer (for selected test cell channel):
OAM F4/F5 fault flow VP AIS, VP RDI, VP AIS+VC AIS,
VC AIS, VC RDI, VP RDI+VC RDI

Background load generator

1 0	U	1	1	
transmitted a	t a selectable rep	petition rate.		
Editor			200	ATM channels
Header				user-selectable
Payload		1	filler byte,	user-selectable

For programming user-defined cell sequences. The sequences can be

Circuit emulation

(for selected test cell channel	.)
Generation of	
an asynchronous channel	
	8448, 34 368, 44 736 kbit/s,
	2048 kbit/s with PCM30 frame structure
ATM channel segmentation.	AAL-1, ITU-T I.363

Receiver unit

Bit rates of framed cell streams	155.520 Mbit/s
Cell scrambler X ⁴³ +1 (ITU-T) ca	an be switched on and off

Measurement types

Error measurement (anomalies), statistics

Detection of the following error types:

Correctable and non-correctable header errors

- AAL-0, cell payload bit errors
- AAL-1, sequence number errors
- AAL-1, SAR-PDU bit errors
- AAL-1 SNP, CRC errors
- AAL-1 SNP, parity errors

ATM performance analysis

- Cell error ratio
- Cell loss ratio
- Cell misinsertion rate
- Mean cell transfer delay
- 2-point cell delay variation measured between minimum and maximum cell transfer delay values
- Cell transfer delay histogram
 128

 Number of classes
 128

 Minimum class width
 160 ns

 Maximum class width
 335 ms

 Settable offset
 0 to 167 ms

 Offset step width
 2.5 μs

Alarm detection (defects)

Physical layer as with ANT-10Gig basic instrument, also:
Loss of Cell Delineation
ATM layer (for selected test cell channel):
OAM F4/F5 fault flowVP AIS, VP RDI, VC AIS, VC RDI

User channel analysis

Concurrent X-Y chart (load vs. time) for:

- All user cells
- Average cell rate of a selected cell channel
- Peak cell rate of a selected cell channel

- Channel utilization histogram:All user cells ("assigned cells")
- A selected cell channel ("user cells")

Cell distribution of a selected cell channel with classification by:

- User cells
- F5 OAM flow
- F4 OAM flow
- User cells with CLP=1

Circuit reassembly

(for selected test cell channel)	
Reassembly	AAL-1, ITU-T I.363
Error measurement on an	
asynchronous channel	1544, 2048, 6312, 8448,
	34 368, 44 736 kbit/s,
2	048 kbit/s with PCM30 frame structure

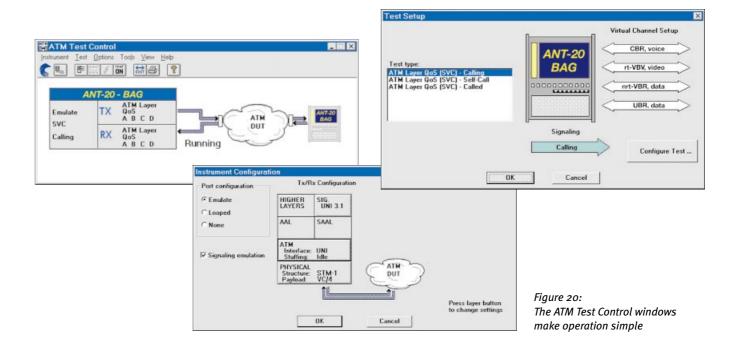
ATM Comprehensive

BN 3060/90.51

includes the function of ATM BASIC BN 3060/90.50 and Broadband Analyzer Generator Module (BAG)

Selection of ready-to-run applications and graphics-supported test settings

The graphical method for making test settings is unique. The way that the ANT-10Gig is connected to the device under test, the protocol layers and settings included in the test, or the ATM services to be tested can be quickly and easily seen. Users can select from a range of predefined test setups or customize their own. Pre-defined ATM channels can be selected from a database or new channels added. Additionally, all characteristics and parameters for each channel are also stored, for example: traffic type, circuit type, header, traffic contract, traffic source. An editor program is provided for defining the test circuits.



Direct testing of all contract parameters

Some of the main tasks facing measurement services are determining whether users are keeping to traffic contracts and how they are doing so, and establishing how the network handles such contracts. These questions can only be answered by means of a test that allows all the major service parameters to be set and measured.

For such applications, the Broadband Module includes an editor that permits all of the contract parameters for the various ATM services to be set for the first time.

For terminal emulation, all contract characteristics and of the traffic model used for the test can be defined with the Channel Editor.

After starting the measurement, the ANT-10Gig generates test traffic using the selected parameters. This allows direct demonstration of the way that the ATM network handles the user traffic and whether the agreed network resources were in fact available.

The source parameters can be varied on-line during the measurement. This makes it possible to detect policing errors or incorrect network access threshold settings quickly and easily.

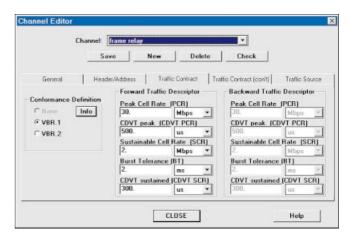


Figure 21: Channel Editor: Setting the traffic descriptor

ATM QoS test with four different SVCs

The ANT-10Gig with BAG can perform SVC and PVC tests on up to four circuits simultaneously. Multi-channel services, such as those used for multimedia applications, can thus be simulated.

Any channel type can be selected from the database or newly defined for each channel.

Real-time measurements conform to the ITU-T O.191 standard which defines the test cell format and the test algorithm. Important source parameters can be regulated on-line during the test.

The results are clearly displayed, with graphics elements used to indicate defects or highlight status information.

Signalling analysis

Sequence errors in the signalling protocol adversely affect correct management of ATM services. They can be detected by recording and displaying all channel states and changes of state in chronological order with timestamp information. The ANT-10Gig constantly monitors the states of the SVCs being tested. The protocol can thus be checked for correctness and any errors detected rapidly. The connection set up time is measured for all test channels.

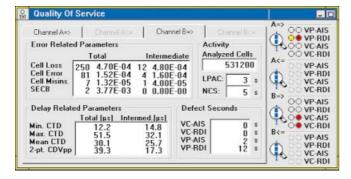


Figure 22: ATM test results for a real-time measurement on channel A

Traffic management and contract optimization

Traffic shaping (single/dual leaky bucket) can be switched on for each ATM channel, even on-line during the measurement.

In addition, the following are displayed per channel with soft LEDs:

- Non Conforming Cells (NCC)
- Dropped Cells (DC)

Using this information it is possible to check whether the UPC (Usage Parameter Control) functions of the network are working and are implemented in compliance with the standard.

At the same time, the degree of utilization of the traffic contracts can be determined.

Using the facilities for simulating all relevant source parameters with up to four competing channels, it is possible to optimize the contract parameters in the network.

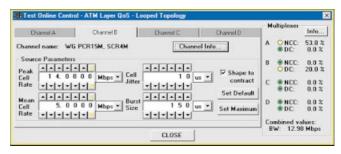


Figure 23: Soft-LED indication of multiplex results

Professional record of results

The ANT-10Gig generates a professional record of instrument settings and test results that is output from a standard printer.

The record can be used for various purposes, e.g.:

- Guarantee documentation
- Acceptance documentation
- Installation record
- Evidence of adherence to contract, etc.

In other words, the ANT-10Gig handles the entire process from measurement through to producing a permanent record of the results.

Broadband Analyzer/Generator

The module includes software test functions for

- ATM Test Controller
- ATM Test Results
- ATM Channel Explorer
- STM-1/STS-3c with C4/SPE ATM mapping to ITU-T G.707, I.432 and ANSI T1.105/107

ATM test controller

Instrument port configurations

Emulation	SVCs, PVCs
Looped signal	PVCs

Test cell channels

4 test channels
settable from 0 to 149.760 Mbit/s
Header settingvia editor
Load setting in kbit/s, Mbit/s, cells/s
Test cell format to ITU-T O.191

ATM service categories

Switched circuits and permanent circuits for:
Constant Bit Rate CBI
Real-time Variable Bit Rate rt-VBI
Non real-time Variable Bit Rate nrt-VBI
Deterministic Bit Rate DBI
Statistical Bit Rate
Unspecified Bit Rate UBI

Signalling emulation Terminal emulation at the UNI as per ITU-T and TATM Forum recommendations
Protocol typesUNI 3.0
UNI 3.1
Q.2931
Q.2961
Test types
Calling, 4 SVCs
Called, 4 SVCs

ATM channel editor

Trame contract:	
Direction type	unidirectional
	bi-directional symmetrical,
	bi-directional asymmetrical

Cell Delay Variation Tolerance sustained CDVT sustained

Traffic descriptor
Peak Cell Rate PCR
Cell Delay Variation Tolerance peak CDVT peak
Sustainable Cell Rate SCR
Burst Tolerance BT

Source parameters Cell clumping,

Burst size

Mean cell rate

Peak cell rate

On-line channel settings

Peak cell rate Cell clumping Mean cell rate Burst size

Traffic management

Us	er-selectable	shaping		
Cl	3R		 	 Single leaky bucket
D.	3R		 	 Single leaky bucket
rt-	VBR		 	 Dual leaky bucket
nr	t-VBR		 	 Dual leaky bucket
SE	R		 	 Dual leaky bucket
U.	3R		 	 Dual leaky bucket

Error insertion

- Correctable and uncorrectable header errors
- Cell loss
- Cell error
- Cell misinsertion
- Severely errored cell blocks

Alarm generation

ATM layer alarms (for all test channels):
OAM F4/F5 fault flowVP AIS, VP RDI, VC AIS, VC RDI

ATM test results

Measurement modes

ISM	In-Service Measurement
OOS	Out-of-Service Measurement

Receiver status (ISM, OOS)

Signal load, bandwidth

Correctable and uncorrectable header errors

Errored seconds LCD, physical layer defects

ATM Quality of Service (QoS) for 4 SVCs or 4 PVCs

- Cell error ratio
- Cell loss ratio
- Cell misinsertion rate
- Mean cell transfer delay
- Maximum cell transfer delay
- Minimum cell transfer delay
- 2-point cell delay variation
- Severely errored cell block ratio

Alarm detection, defects (ISM, OOS)

Signalling analysis

Channel set-up time

Channel status with interpretation and timestamp

Representation of ATM QoS for the SVC after clearing down the circuit.

ATM channel explorer (ISM, OOS)

Channel search:

CLP = 1 BandWidth (%) CLP1-BW
Average BandWidth AvBW
Current BandWidth CuBW

Aging (switchable function)

Sorts out inactive channels from the activity list.

AAL analysis:

Automatic determination of AAL type for 1000 ATM channels. Graphic display of distribution.

Trouble scan:

Automatic determination of VC AIS, VC RDI, VP AIS and VP RDI in up to $1000~\mathrm{ATM}$ channels.

Add ATM SDH

BN 3060/90.52

The ATM mapping options provide further frame structures for interfaces conforming to ITU-T G.804/832/707.

Corresponding physical layer measurement functions are offered by the mapping options for the interfaces. These include error and alarm insertion, error measurement and alarm detection.

The following ATM mappings are included:

E4 (140 Mbit/s) ATM mapping

E3 (34 Mbit/s) ATM mapping

E1 (2 Mbit/s) ATM mapping

STM-1/VC3 ATM mapping

Add ATM SONET

BN 3060/90.53

The ATM mapping options provide further frame structures for interfaces conforming to ANSI T1.105/107.

Corresponding physical layer measurement functions are offered by the mapping options for the interfaces. These include error and alarm insertion, error measurement and alarm detection.

The following ATM mappings are included:

STS-1/STS-3 ATM mapping

Bit rate

DS3 (45 Mbit/s) ATM mapping and STS-1 DS3 ATM mapping PLCP-based mapping HEC-based mapping	Circuit emulation Generation of asynchronous channels: 1.544, 2.048, 6.312, 8.448, 34.368, 44.736 kbit/s, 2.048 kbit/s with PCM30 frame structure ATM channel segmentation
Bit rate	Title chamber segmentation ++++++++++++++++++++++++++++++++++++
DS1 (1.5 Mbit/s) ATM mapping Bit rate	Error measurement, anomalies, statistics Detection of following error types: - Correctable and non-correctable header errors - AAL-0, cell payload bit error - AAL-1, sequence number error
STM-4c/OC-12c ATM testing BN 3060/90.91	AAL-1, SAR-PDU bit errorAAL-1 SNP, CRC error
Only in conjunction with BN 3060/90.50 and BN 3060/91.11 or BN 3035/91.12	- AAL-1 SNP, parity error
Signal structure (TC sublayer) contiguous concatenation to T1.646, I.432 and af-phy-0046.000 Cell scrambler X ⁴³ +1 (ITU-T) can be switched off	ATM performance analysis - Cell error ratio - Cell loss ratio - Cell misinsertion rate - Mean cell transfer delay
Test cell channel Adjustable from 0 to 149.760 Mbit/s	 2-point cell delay variation Measured between greatest and smallest value of cell transfer delay Cell transfer delay histogram:
Header setting editor Load setting in Mbit/s, Cells/sec, %	Number of classes 128 Min. class width 160 ns Max. class width 335 ms
Test cells, pay load pattern AAL-0, pseudorandom bit sequences (PRBS) 2 ¹¹ -1, 2 ¹⁵ -1, 2 ²³ -1	Adjustable offset 0 to 167 ms Offset steps 2.5 μs
AAL-1, pseudorandom bit sequences (PRBS)	Alarm detection, defects (ISM, OoS) Loss of Cell Delineation
Test cells for ATM performance analysis: Sequence number	ATM layer (for any selected cell channel) OAM F4/F5 fault flow VP AIS, VP RDI, VC AIS, VC RDI
Timestamp 4 bytes Error checking CRC-16	Traffic channel analysis Time chart simultaneously for — All traffic cells
Load profiles	Average cell rate of any selected cell channel
Equidistant, setting range	- Peak cell rate of any selected cell channel Display in
Peak cell rate 1 to 25% Mean cell rate 1 to 25% Burst size 4 to 4092 cell times	Channel utilization histogram – All assigned cells – One selected cell channel (user cells)
Burst period 8 to 131 068 cell times Error insertion	Cell distribution in traffic channel Classification of one selected cell channel by
Physical layer like basic ANT-10Gig instrument ATM layer, AAL:	User cellsF5 OAM flow
 Correctable and non-correctable header errors AAL-0, cell payload bit error 	F4 OAM flowUser cells with CLP=1
AAL-1, sequence number errorAAL-1, SAR-PDU bit error	Circuit reassembly
- AAL-1 SNP, CRC error	Reassembly
 AAL-1 SNP, parity error 	Error measurement on asynchronous channels:
Resolution: Single error, error ratio, n errors in m cells	1.544, 2.048, 6.312, 8.448, 34.368, 44.736 kbit/s, 2.048 kbit/s with PCM30 frame structure
Alarm generation Loss of Cell Delineation LCD ATM layer (for any selected cell channel) OAM F4/F5 fault flow	
Background load generator 1 channel can be switched ON/OFF Residual bandwidth up to 599.040 Mbit/s Header is freely definable	

AUTO/Remote

ANT-10Gig applications in the remote controlled production environment

V.24/RS232 Remote Control Interface	BN 3035/91.01
Remote control of instrument functions using	
SCPI command structure	
Interface	V.24/RS232

GPIB (PCMCIA) Remote Control Interface BN 3035/92.10 Remote control of instrument functions using SCPI command structure. A GPIB adapter card for the ANT-10Gig PCMCIA interface is supplied with this option Interface
TCP/IP Remote Control Interface Remote control of instrument functions using BN 3035/91.11
SCPI command structure Interface

LabWindows driver BN 3035/95.99

Simplifies creation of remote-control programs for automated testing using LabWindows. The drivers can be used with options BN 3035/91.01 and BN 3035/92.10.

Simplified test automation (Figure 24)

Computer Aided Test Sequencer (CATS) and Test Case Library

The Test Sequencer is the ideal tool for rapid, simple adaptation and automatic performance of complete test sequences on the ANT-10Gig (CATS = Computer Aided Test Sequence). This saves time where repetitive tests are required in the production, installation and monitoring of SDH, SONET and ATM network elements. The comprehensive test case library includes solutions for various applications, such as BERTs, alarm sensor tests, jitter, offset and pointer tests and monitoring ATM Quality of Service (QoS) parameters.

Once created, test sequences are started with a single mouse click.

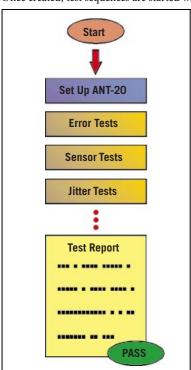


Figure 24: Automatic test sequences with the ANT-10Giq

A report in ASCII format for documentation purposes is compiled during the measurement. All test cases are pre-defined and ready to run. They can also be easily customized.

More information is found in the data sheet "Test Automation and Remote Control".

Remote Operation

BN 3035/95.30

These options allow operation of the ANT-10Gig from a Windows® PC. The complete ANT-10Gig user interface is transferred to the PC screen via modem or LAN link. This means that all the functions of the instrument can be used from any remote location. The results are simply transferred to the controlling PC for further processing. Applications include troubleshooting networks or centralized operation of test instrumentation and devices in the production and system test environment.

Remote Operation via the included Ethernet Interface and Remote Operation via Modem

Provides remote operation via a PCMCIA or external modem (V.24) which must be purchased separately.

Calibration

Calibration report

Calibration is carried out in accordance with a quality management system certified to ISO 9001.

Recommended confirmation interval 24 months

Training courses

ANT Training

"SDH/SONET Troubleshooting" BN 3035/89.01 (Two-day interactive workshop on SDH/SONET basics in connection

with important measurement applications and presentation of Acerna test solutions). "Synchronization" BN 3035/89.02

(Half-day interactive workshop on aspects of synchronization and typical measurement applications).

"Solving Jitter Problems" BN 3035/89.03

(Half-day interactive workshop on jitter problems and presentation of Acterna test solutions).

"SDH/SONET Quality of Service" BN 3035/89.04

(Half-day interactive workshop on performance measurements to G.821, G.826 and M.2100).

"Optimizing Your SDH/SONET Network" BN 3035/89.05

(One-day interactive workshop on measurement applications and operation of the ANT-10Gig).

Information via Internet

http://www.ant-20.acterna.com

Ordering Information

8			
ANT-10Gig SDH version	BN 3060/35	Optical Attenuator (plug-in) SC-PC, 1310 nm, 15 dB	BN 2060/00.61
Includes: • Mainframe, touchscreen • STM-64/OC-192 combined with STM-4c, STM-1	l6c and STM-64c	Optical Power Splitter (90%/10%) Includes three optical adapters – please select.	BN 3060/91.05
STS-12c SPE, STS-48c SPE, STS-192c SPE	01111 010,		
• Mappings for STM-1: DS1, E1, DS3, E3, E4		Optical Test Adapters	DN 20 (0/00 22
 Electrical interfaces: STM-1, E1, E3, E4 APS, TCM analysis, OH capture, OH sequencing 		ST type (AT&T) HMS-10/A, HFS-13/A (Diamond)	BN 2060/00.32 BN 2060/00.34
 Two optical adaptors to be selected 		HMS-10, HFS-13 (Diamond)	BN 2060/00.35
•		"Keyed Biconic", Twist-Proof (AT&T)	BN 2060/00.37
		D4 (NEC) DIN 47256	BN 2060/00.40 BN 2060/00.50
		FC, FC-PC (NTT)	BN 2060/00.51
Outland		E 2000 (Diamond)	BN 2060/00.53
Options		SC, SC-PC (NTT)	BN 2060/00.58
Electrical Interfaces at 9953 Mbit/s	BN 3060/91.48	Acterna offers a wide range of optical power meters, and attenuators. Contact your local sales representat	
Please order with the mainframe as a subsequent upgrade is not possible.		0.172 Jitter and Wander	
•		O.172 Jitter/Wander Packet up to 155 Mbit/s	BN 3060/91.30
Add SONET	BN 3060/90.03	Includes MTIE/TDEV offline analysis O.172 Jitter/Wander Packet up to 622 Mbit/s	BN 3060/91.31
STM-0 mappings		Includes MTIE/TDEV offline analysis	DIN 3000/91.31
STM-0 and VT2 SPE (2 Mbit/s) STM-0 and VT1.5 SPE g (1.5 Mbit/s)		O.172 Viender Applymen et 0053 Mbit/s	BN 3060/91.60
VT6 SPE (6 Mbit/s)		O.172 Wander Analyzer at 9953 Mbit/s Includes MTIE/TDEV offline analysis	BN 3060/91.61
STM-0 and STS-1 SPE (34/45 Mbit/s)		Requires Jitter 10 Gbit/s BN 3060/91.60	DN 2060/01 62
BERT (1.5/6/45 Mbit/s)		O.172 Wander Generator Requires Jitter at 10 Gbit/s BN 3060/91.60 and either Jitter Generator	BN 3060/91.62 erator
Add BERT SONET only (interfaces 1.5/6/45 Mbit/s)	BN 3060/90.34	at 155 Mbit/s BN 3035/90.81 or BN 3060/91.30 or BN 3060/91.	31.
Drop & Insert	BN 3060/90.10	ATM Functions	
		ATM Basic for STM-1/STS-3c	BN 3060/90.50
PDH 64k/140M MUX/DEMUX chain	BN 3060/90.11	ATM Comprehensive Includes ATM BASIC and BAG	BN 3060/90.51
M13 MUX/DEMUX chain	BN 3060/90.12		
		Add ATM SONET Requires ATM module BN 3060/90.50 or BN 3060/90.51	BN 3060/90.53
Optical Interfaces Include two optical adapters – please select.		STS-1 (51 Mbit/s) ATM mapping	
The following options BN 3060/91.01 to /91.12 are alternatives.		DS3 (45 Mbit/s) ATM mapping	
Optical STM-0/1, OC-1/3, 1310 nm	BN 3060/91.01	DS1 (1.5 Mbit/s) ATM mapping	
Optical STM-0/1, OC-1/3, 1310 & 1550 nm Optical STM-0/1/4, OC-1/3/12, 1310 nm	BN 3060/91.02 BN 3060/91.11	Add ATM SDH	BN 3060/90.52
Optical STM-0/1/4, OC-1/3/12, 1310 & 1550 nm	BN 3060/91.12	Requires ATM module BN 3060/90.50 or BN 3060/90.51	
The options BN 3060/91.50 to /91.53 are alternatives. Optical STM-16/OC-48, 1310 nm	BN 3060/91.51	E4 (140 Mbit/s) ATM mapping E3 (34 Mbit/s) ATM mapping	
Optical STM-16/OC-48, 1550 nm	BN 3060/91.50	E1 (2 Mbit/s) ATM mapping	
Optical STM-16/OC-48, 1310/1550 nm switchable	BN 3060/91.52	VC-3 ATM mapping in STM-1 (AU-3/AU-4)	
STM //s/OC 12s entions		OC-12c/STM-4c ATM Testing	BN 3060/90.91
STM-4c/OC-12c options STM-4c/OC-12c ATM Testing	BN 3060/90.91	Requires Optical Module BN 3060/91.11 or /91.12	
Requires Optical Module BN 3060/91.11 or /91.12		Tost Automotion	
and ATM BASIC BN 3060/90.50 STM-4c/OC-12c Virtual Concatenation	BN 3060/90.92	Test Automation Test Sequencer CATS BASIC	BN 3035/95.90
Requires BN 3060/90.90 or /90.91		Test Sequencer CATS PROFESSIONAL	BN 3035/95.95
Optical Packages		Remote Control Interfaces	
Include optical interfaces from 52 Mbit/s to 2488 Mbit/s and for	ır	V.24/RS232 Remote Control Interface	BN 3035/91.01
optical adapters – please select. Optics STM-0/1/4/16, OC-1/3/12/48, 1310 nm	BN 3060/91.17	GPIB Remote Control Interface TCP/IP Remote Control Interface	BN 3035/92.10 BN 3035/92.11
Optics STM-0/1/4/16, OC-1/3/12/48, 1510 hill Optics STM-0/1/4/16, OC-1/3/12/48, 1550 nm	BN 3060/91.17 BN 3060/91.18	LabWindows CVI driver	BN 3035/95.99
Optics STM-0/1/4/16, OC-1/3/12/48, 1310&1550 nm	BN 3060/91.19	D	
Optics STM-0/1/4, OC-1/3/12, 1310 nm Optics STM-16, OC-48, 1550 nm	BN 3060/91.20	Remote Operation Remote Operation	BN 3035/95.30
1		Terriote Operation	DIA JUJJ/73.JU

Calibration report

BN 3060/94.01 (Calibration is carried outin accordance with quality management system crtified to ISO 9001.)

Accessories

Transport case for ANT-10Gig BN 3035/92.03 External keyboard (UK/US) BN 3035/92.04 Decoupler (-20 dB, 1.6/5.6 jack plug) BN 3903/63 TKD-1 probe, 48 to 8500 kbit/s BN 822/01 TSR-37 Rubidium Timing Source Reference DA 3700/00 PenBERT mini PCM monitor (E1) BN 4555/11 (see PenBERT data sheet for details)

Training courses

Location: 72800 Eningen u.A., Germany Information about availability and other locations available on request.

"SDH/SONET troubleshooting"	BN 3035/89.01
"Synchronization"	BN 3035/89.02
"Solving Jitter Problems"	BN 3035/89.03
"SDH/SONET Quality of Service"	BN 3035/89.04
"Optimizing Your SDH/SONET Network"	BN 3035/89.05